Search Notes				
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Application No.	Applicant(s)
09/980,754	LERCH ET AL.
Examiner	Art Unit
Julio J. Maldonado	2823

CEARCUED				
SEARCHED				
Class	Subclass	Date	Examiner	
438	795, 796, 797, 798, 413, 419	3/1/2004	en	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	L		

SEARCH NOT (INCLUDING SEARCH		()
	DATE	EXMR
East (USPAT; USPGPUB) forming with silicon with (nitride or oxynitride) with doped with substrate with thickness	3/1/2004	yn
(forming with silicon with (nitride or oxynitride) with doped with substrate) and thickness with ("2 nm" or "20 angstroms" or	3/1/2004	kin
"4 nm" or "40 angstroms")	3/1/2004	jus
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